ECE 6450 Homework #7 Solutions

1.) Explain why plasma etching trends have been moving toward lower pressures while deposit ion trends have been moving toward higher pressures.

In many plasma etching applications (but not all) high degrees of anisotropy is desired. Thus, o ne desires a low pressure process to allow a longer mean free path and a more directional deliver y of the etching gases. Again, biases (either plasma induced or added DC biases) can also incre ase this directionality. For deposition, most processes (but not all, especially III-V technolog y) require conformal coatings with equal thicknesses on all surfaces including sidewalls and corn ers. Thus, a shorter mean free path resulting from higher pressures allows more uniform coati ngs. However, to high of a pressure can result in exterior corners (like the top corners of a tren ch) being deposited faster than the flat areas (higher incident collection angles as discussed in cla ss).

2.) When dilute amounts of oxygen are introduced into a CF₄ plasma process, a scavenged byp roduct gas like CO (carbon monoxide) is produced. A.) If the gases are introduced to a large ch amber (infinite conductance) with an exit tube with a conductance of 100 liters/(sec-torr) to a roo ts blower pump at 50 millitorr (50e-3 torr), what is the maximum possible throughput (in sccm) o f CF₄ and CO respectively? (Assume the vapor pressure of CF₄ is 1 torr and the vapor pressure o f CO is 1000 torr at the process temperature). B.) If the chamber has a volume of 10 liters an d is maintained at 1 torr pressure, what (approximate) average time is required to purge the two g ases (this is effectively the speed for which a process change can be made and is why minimizati on of the volume of process chambers is important)? C.) How does this difference in the rate of removal of CO and CF₄ effect the average carbon content in the chamber for the cases where oxygen is not present verses when it is present? D.) What effect does the change in carbon co ntent have on the sidewall polymerization and why (Assume RIE conditions)? E.) What effect to express the oxygen have on the anisotropy?

A.) What flow regime are we in? The statements, roots blower, vapor pressures of 1 and 100 0 torr, 50 millitorr, and C=100 [liters/(sec-torr)] each indicate the viscous flow regime. Thus, $Q=K(P^2_{upstream}-P^2_{downstream})$ where C is 100 liters/(sec-torr). To a first approximation, assuming i ndependent, non-interacting gases, we can approximate the gases as being independent systems. But we were not given K: Therefore similar to example 10.2,

$$Q = C(P_{upstream} - P_{downstream})$$

$$P_{average}Q = C(P_{upstream} - P_{downstream})P_{average}$$

$$P_{average}Q = C(P_{upstream} - P_{downstream})\frac{(P_{upstream} + P_{downstream})}{2}$$

$$P_{average}Q = C(P_{upstream}^2 - P_{upstream}P_{downstream} + P_{upstream}P_{downstream} - P_{downstream}^2)\frac{1}{2}$$

$$Q = \left(\frac{C}{2P_{average}}\right)(P_{upstream}^2 - P_{downstream}^2)$$

$$Q = K(P_{upstream}^2 - P_{downstream}^2)$$

$$K = \left(\frac{C}{2P_{average}}\right)$$

Therefore:

CF₄: Q=(100/[2 ($\frac{1}{2}(1+0.05)$)]) (1²-0.05²)= 95 torr-liters/sec or 7500 sccm. CO: Q=(100/[2 ($\frac{1}{2}(1000+0.05)$)]) (1000²-0.05²)= 9.9e4 torr-liters/sec or 7,894,000 sccm.

B.) The above values are the maximum achievable throughput. Note that the CO can be pumpe d faster than the CF_4 . Since the chamber is held at 1 torr, we can calculate the approximate ti me to empty the chamber of these gases as,

CF₄: Time = Volume x Pressure/Throughput = 10 (1)/99.75 = 0.1 seconds CO: Time = Volume x Pressure/Throughput = 10 (1)/166 = 10 microseconds

Note: in reality the approximation of gases as independent in flow, is a poor approximation beca use the slower pumped gas can be "pushed along" by the faster pumped gas. Also note that the se pressures are not "the real" vapor pressures of these gases and are for illustration only. Thus, real gas systems switch slower than that presented here but the concept is similar.

C.) If the throughput of CF_4 is constant into the chamber, the more rapid removal of CO than C F_4 when oxygen is introduced results in a lower average carbon concentration in the reaction cha mber compared to when oxygen is not present.

D.) Since carbon concentrations are lowered with the introduction of oxygen, less carbon is av ailable to deposit and polymerize.

E.) From (D.) above, the sidewalls are less protected and etched more readily, decreasing the a nisotropy.

3.) What percentage of gas molecules (assume 3 angstrom molecular diameter) traveling a dist ance of 50 cm has underwent a randomizing scattering event at 0.5 Pa (sputtering chamber) and a t 10^{-4} Pa (evaporator chamber)? You may use the expression for scattering probability,

 $\frac{n}{n_o} = 1 - e^{\frac{-d}{\lambda}}$ where n is the number of molecules having been scattered, n_o is the total number of

f molecules, d is the distance traveled and λ is the mean free path between collisions.

Assume room temperature:

$$\lambda = \frac{1}{\sqrt{2}\pi d^2 n} = \frac{kT}{\sqrt{2}\pi d^2 P} = \frac{1.38e - 23(300)}{\sqrt{2} 3.14159(3e - 10)^2 P}$$

Thus, l=2.07cm for 0.5 Pa while l=10,366 cm for 1e-4 Pa. Plugging these numbers into the above equation using d=50 cm,

 $n/n_o=1$ (or 100%) for the sputtering chamber at 0.5Pa $n/n_o=0.0048$ (or 0.48%) for the evaporator chamber at 1e-4Pa

Note that this is why the evaporator is highly directional in its deposition whereas the sputtering chamber is not.

4.) Look over example 12.1 in your book (no need to turn it in).

Each semester, I get comments that the book answer is incorrect. This is not true. The key to this problem is in the units. Some useful insights and conversion factors are: Boltzmann's Constant Joules/Kelvin 1 Joule=Kg m^2/sec^2 1 atomic mass unit (amu) =1.66e-27 Kg

Using these conversion factors, the units and numbers work out as described in the problem.